# ICX055AL

# 1/3-inch CCD Image Sensor for CCIR B/W Camera

#### **Description**

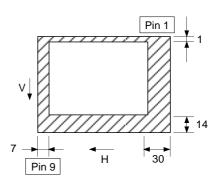
The ICX055AL is an interline CCD solid-state image sensor suitable for CCIR 1/3-inch B/W video cameras. High sensitivity is achieved through the adoption of HAD (Hole-Accumulation Diode) sensors.

This chip features a field period readout system, and an electronic shutter with variable charge-storage time.

# 16 pin DIP (Plastic)

#### **Features**

- High sensitivity (+3dB compare with ICX045BLA) and low dark current
- Continuous variable-speed shutter 1/50s (Typ.), 1/120s to 1/10000s
- · Low smear
- · Excellent antiblooming characteristics
- Horizontal register: 5V driveReset gate: 5V drive



Optical black position

(Top View)

#### **Device Structure**

• Optical size: 1/3-inch format

• Number of effective pixels: 500 (H)  $\times$  582 (V) approx. 290K pixels • Number of total pixels: 537 (H)  $\times$  597 (V) approx. 320K pixels

• Interline CCD image sensor

• Chip size: 6.00mm (H)  $\times$  4.96mm (V) • Unit cell size: 9.8 $\mu$ m (H)  $\times$  6.3 $\mu$ m (V)

Optical black: Horizontal (H) direction: Front 7 pixels, Rear 30 pixels

Vertical (V) direction: Front 14 pixels, Rear 1 pixel

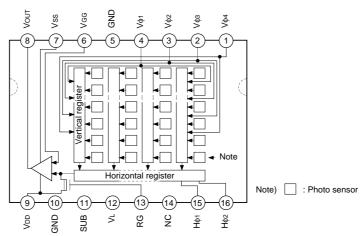
• Number of dummy bits: Horizontal 16

Vertical 1 (even field only)

• Substrate material: Silicon

# **Block Diagram and Pin Configuration**

(Top View)



# **Pin Description**

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	Vф4	Vertical register transfer clock	9	VDD	Output amplifier drain supply
2	Vфз	Vertical register transfer clock	10	GND	GND
3	Vф2	Vertical register transfer clock	11	SUB	Substrate (Overflow drain)
4	Vф1	Vertical register transfer clock	12	VL	Protective transistor bias
5	GND	GND	13	RG	Reset gate clock
6	Vgg	Output amplifier gate bias	14	NC	
7	Vss	Output amplifier source	15	Нф1	Horizontal register transfer clock
8	Vouт	Signal output	16	Нф2	Horizontal register transfer clock

# **Absolute Maximum Ratings**

	Item	Ratings	Unit	Remarks
Substrate voltage SUB – G	SND	-0.3 to +55	V	
Supply voltage	VDD, VOUT, Vss – GND	-0.3 to +18	V	
Supply voltage	VDD, VOUT, VSS – SUB	-55 to +10	V	
Vertical alack input valtage	Vφ1, Vφ2, Vφ3, Vφ4 – GND	-15 to +20	V	
Vertical clock input voltage	Vφ1, Vφ2, Vφ3, Vφ4 – SUB	to +10	V	
Voltage difference between	n vertical clock input pins	to +15	V	*1
Voltage difference between	n horizontal clock input pins	to +17	V	
Hφ1, Hφ2 – Vφ4		-17 to +17	V	
Hφ1, Hφ2, RG, Vgg – GND		-10 to +15	V	
Hφ1, Hφ2, RG, Vgg – SUB		-55 to +10	V	
VL – SUB		-65 to +0.3	V	
V\$1, V\$2, V\$3, V\$4, VDD, VC	DUT — VL	-0.3 to +30	V	
RG – VL		-0.3 to +24	V	
Vgg, Vss, Hφ1, Hφ2 – VL		-0.3 to +20	V	
Storage temperature		-30 to +80	°C	
Operating temperature		-10 to +60	°C	

<sup>\*1 +27</sup>V (Max.) when clock width<10µs, clock duty factor<0.1%.

#### **Bias Conditions**

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain voltage	VDD	14.55	15.0	15.45	V	
Output amplifier gate voltage	Vgg	1.75	2.0	2.25	V	
Output amplifier source	Vss		unded \ OΩ resis			±5%
Substrate voltage adjustment range	VsuB	9.0		18.5	V	*1
Fluctuation range after substrate voltage adjustment	ΔVsub	-3		+3	%	
Reset gate clock voltage adjustment range	Vrgl	1.0		4.0	V	*1
Fluctuation range after reset gate clock voltage adjustment	$\Delta V_RGL$	-3		+3	%	
Protective transistor bias	VL		*2	•		

#### **DC Characteristics**

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Output amplifier drain current	IDD		3		mA	
Input current	lin1			1	μΑ	*3
Input current	lın2			10	μΑ	*4

<sup>\*1</sup> Indications of substrate voltage (VSUB) · reset gate clock voltage (VRGL) setting value.

The setting values of substrate voltage and reset gate clock voltage are indicated on the back of the image sensor by a special code. Adjust substrate voltage (Vsub) and reset gate clock voltage (VRGL) to the indicated voltage. Fluctuation range after adjustment is ±3%.

Vsub code one character indication  $\Box$   $\Box$  VrgL code one character indication  $\uparrow$   $\uparrow$ 

VRGL code VSUB code

Code and optimal setting correspond to each other as follows.

Vrgl code	1	2	3	4	5	6	7
Optimal setting	1.0	1.5	2.0	2.5	3.0	3.5	4.0

Vsub code	Е	f	G	h	J	K	L	m	Ν	Р	Q	R	S	Т	C	<	W	Х	Υ	Z
Optimal setting	9.0	9.5	10.0	10.5	11.0	11.5	12.0	12.5	13.0	13.5	14.0	14.5	15.0	15.5	16.0	16.5	17.0	17.5	18.0	18.5

 "5L" 
$$\rightarrow$$
 VRGL = 3.0V  
VSUB = 12.0V

- \*3 1) Current to each pin when 18V is applied to VDD, VOUT, Vss and SUB pins, while pins that are not tested are grounded.
  - 2) Current to each pin when 20V is applied sequentially to  $V\phi_1$ ,  $V\phi_2$ ,  $V\phi_3$  and  $V\phi_4$  pins, while pins that are not tested are grounded. However, 20V is applied to SUB pin.
  - 3) Current to each pin when 15V is applied sequentially to RG, Hφ1, Hφ2 and VGG pins, while pins that are not tested are grounded. However, 15V is applied to SUB pin.
  - 4) Current to V<sub>L</sub> pin when 30V is applied to Vφ1, Vφ2, Vφ3, Vφ4, VDD and VOUT pins or when, 24V is applied to RG pin or when, 20V is applied to VgG, Vss, Hφ1 and Hφ2 pins, while V<sub>L</sub> pin is grounded. However, GND and SUB pins are left open.

<sup>\*2</sup> VL setting is the VvL voltage of the vertical transfer clock waveform.

<sup>\*4</sup> Current to SUB pin when 55V is applied to SUB pin, while pins that are not tested are grounded.

# **Clock Voltage Conditions**

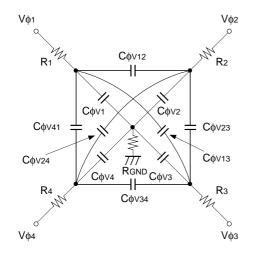
Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Readout clock voltage	Vvт	14.55	15.0	15.45	V	1	
	Vvh1, Vvh2	-0.05	0	0.05	V	2	VvH = (VvH1 + VvH2) /2
	VvH3, VvH4	-0.2	0	0.05	V	2	
	VVL1, VVL2, VVL3, VVL4	-9.0	-8.5	-8.0	V	2	VVL = (VVL3 + VVL4) /2
	Vφv	7.8	8.5	9.05	V	2	$V\phi V = VVHN - VVLN (n = 1 to 4)$
Vertical transfer clock	Vvh1 — Vvh2			0.1	V	2	
voltage	Vvнз — Vvн	-0.25		0.1	V	2	
	VvH4 — VvH	-0.25		0.1	V	2	
	Vvнн			0.5	V	2	High-level coupling
	Vvhl			0.5	V	2	High-level coupling
	Vvlh			0.5	V	2	Low-level coupling
	VVLL			0.5	V	2	Low-level coupling
Horizontal transfer	Vфн	4.75	5.0	5.25	V	3	
clock voltage	VHL	-0.05	0	0.05	V	3	
Reset gate clock	Vørg	4.5	5.0	5.5	V	4	*1
voltage	Vrglh – Vrgll			0.8	V	4	Low-level coupling
Substrate clock voltage	Vфsuв	22.5	23.5	24.5	V	5	

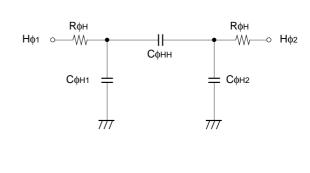
<sup>\*1</sup> The reset gate clock voltage need not be adjusted when reset gate clock is driven when the specifications are as given below. In this case, the reset gate clock voltage setting indicated on the back of the image sensor has not significance.

Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Reset gate clock	Vrgl	-0.2	0	0.2	V	4	
voltage	Vørg	8.5	9.0	9.5	V	4	

# **Clock Equivalent Circuit Constant**

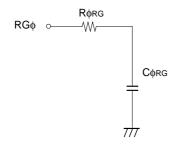
Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Capacitance between vertical transfer	Сфу1, Сфуз		1500		pF	
clock and GND	Сф∨2, Сф∨4		820		pF	
	Сф∨12, Сф∨34		470		pF	
Capacitance between vertical transfer	Сф∨23, Сф∨41		230		pF	
clocks	Сф∨13		150		pF	
	Сф∨24		230		pF	
Capacitance between horizontal transfer clock and GND	Сфн1, Сфн2		47		pF	
Capacitance between horizontal transfer clocks	Сфнн		47		pF	
Capacitance between reset gate clock and GND	СфRG		5		pF	
Capacitance between substrate clock and GND	Сфѕив		320		pF	
Variant transfer along to arise register	R1, R3		51		Ω	
Vertical transfer clock series resistor	R2, R4		100		Ω	
Vertical transfer clock ground resistor	RGND		15		Ω	
Horizontal transfer clock series resistor	Rфн		10		Ω	
Reset gate clock series resistor	Rørg		40		Ω	





Vertical transfer clock equivalent circuit

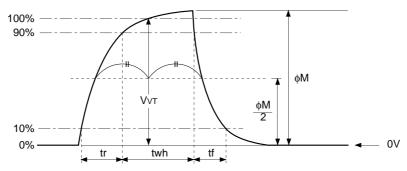
Horizontal transfer clock equivalent circuit



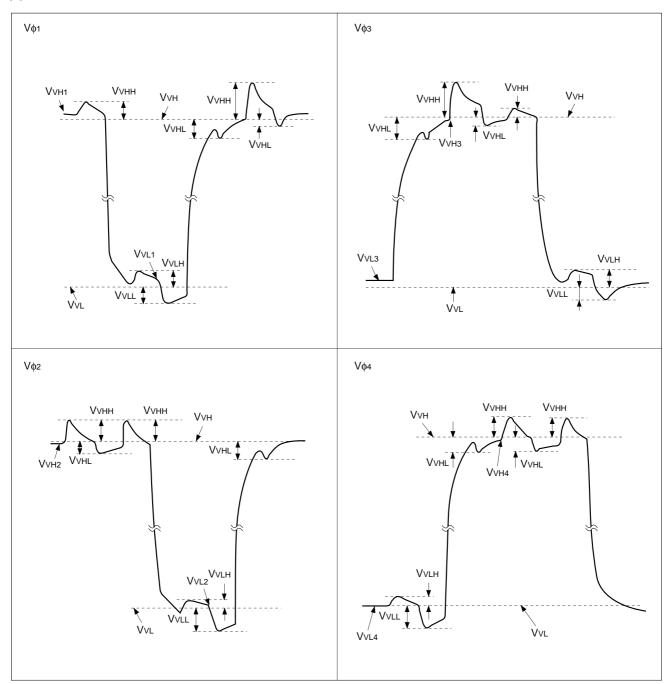
Reset gate clock equivalent circuit

#### **Drive Clock Waveform Conditions**

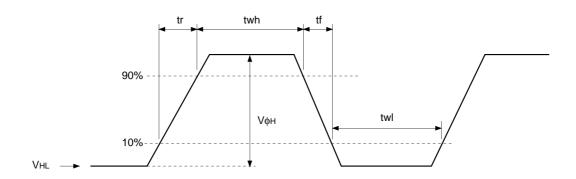
# (1) Readout clock waveform



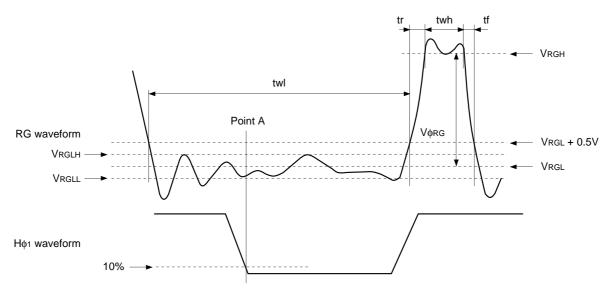
# (2) Vertical transfer clock waveform



# (3) Horizontal transfer clock waveform



# (4) Reset gate clock waveform



VRGLH is the maximum value and VRGLL is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG.

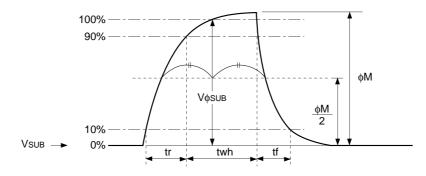
In addition, VRGL is the average value of VRGLH and VRGLL.

$$V_{RGL} = (V_{RGLH} + V_{RGLL})/2$$

Assuming VRGH is the minimum value during the interval twh, then:

$$V\phi RG = VRGH - VRGL$$

# (5) Substrate clock waveform



# **Clock Switching Characteristics**

Item	Symbol		twh			twl			tr			tf		Unit	Remarks	
nem	Symbol	Min.	Тур.	Max.	Min.	Тур.	Max.	Min.	Тур.	Мах.	Min.	Тур.	Мах.	Offic	Remarks	
Readout clock	VT	2.3	2.5						0.5			0.5		μs	During readout	
Vertical transfer clock	Vφ1, Vφ2, Vφ3, Vφ4										0.015		0.25	μs	*1	
Horizontal transfer clock	Нф	37	41		38	42			12	15	*2	10	15	ns	During imaging	
Horizontal transfer clock	Нф1		5.6						0.012			0.012		μs	During parallel-	
Horizontal transfer clock	Нф2					5.6			0.012			0.012		μs	serial conversion	
Reset gate clock	φRG	11	15		75	79			6.5			4.5		ns		
Substrate clock	фѕив	1.5	2.0							0.5			0.5	μs	During drain charge	

<sup>\*1</sup> When vertical transfer clock driver CXD1250 is used.

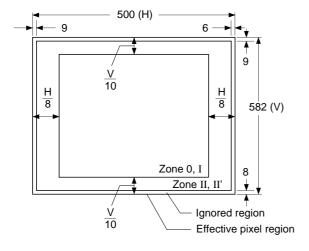
<sup>\*2</sup>  $tf \ge tr - 2ns$ 

# **Image Sensor Characteristics**

 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Min.	Тур.	Max.	Unit	Measurement method	Remarks
Sensitivity	S	420	500		mV	1	
Saturation signal	Vsat	630			mV	2	Ta = 60°C
Smear	Sm		0.005	0.007	%	3	
	CLI			20	%	4	Zone 0, I
Video signal shading	SH			25	%	4	Zone 0 to II'
Dark signal	Vdt			2	mV	5	Ta = 60°C
Dark signal shading	ΔVdt			1	mV	6	Ta = 60°C
Flicker	F			2	%	7	
Lag	Lag			0.5	%	8	

# Zone Definition of Video Signal Shading



#### **Image Sensor Characteristics Measurement Method**

#### Measurement conditions

 In the following measurements, the substrate voltage and the reset gate clock voltage are set to the values indicated on the device, and the device drive conditions are at the typical values of the bias and clock voltage conditions.

2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black (OB) level is used as the reference for the signal output, and the value measured at point [\*A] in the drive circuit example is used.

#### O Definition of standard imaging conditions

#### 1) Standard imaging condition I:

Use a pattern box (luminance  $706\text{cd/m}^2$ , color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter and image at F8. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity.

#### 2) Standard imaging condition II:

Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter. The luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm.

#### Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/250s, measure the signal output (Vs) at the center of the screen and substitute the value into the following formula.

$$S = Vs \times \frac{250}{50} [mV]$$

#### 2. Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with average value of the signal output, 200mV, measure the minimum value of the signal output.

#### 3. Smear

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity to 500 times the intensity with average value of the signal output, 200mV. When the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value VSm [mV] of the signal output and substitute the value into the following formula.

$$Sm = \frac{VSm}{200} \times \frac{1}{500} \times \frac{1}{10} \times 100 \text{ [\%] (1/10V method conversion value)}$$

#### 4. Video signal shading

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity so that the average value of the signal output is 200mV. Then measure the maximum (Vmax [mV]) and minimum (Vmin [mV]) values of the signal output and substitute the values into the following formula.

$$SH = (Vmax - Vmin)/200 \times 100 [\%]$$

#### 5. Dark signal

Measure the average value of the signal output (Vdt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

#### 6. Dark signal shading

After measuring 5, measure the maximum (Vdmax [mV]) and minimum (Vdmin [mV]) values of the dark signal output and substitute the values into the following formula.

$$\Delta Vdt = Vdmax - Vdmin [mV]$$

#### 7. Flicker

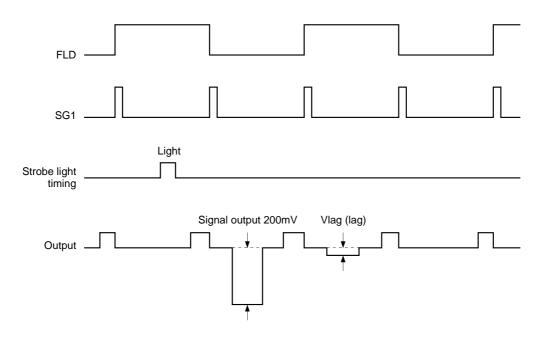
Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the signal output is 200mV, and then measure the difference in the signal level between fields ( $\Delta$ Vf [mV]). Then substitute the value into the following formula.

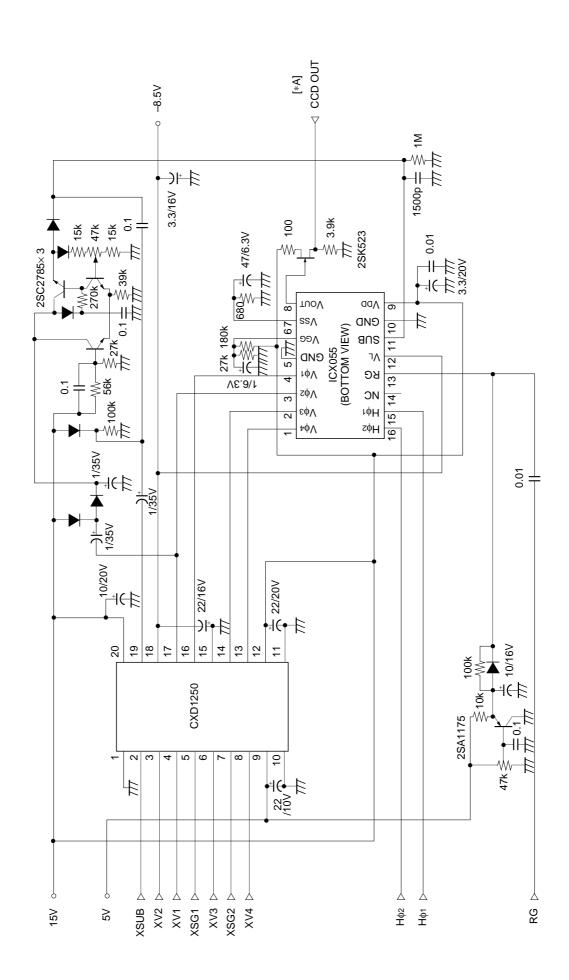
$$F = (\Delta Vf/200) \times 100 [\%]$$

#### 8. Lag

Adjust the signal output value generated by strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Vlag). Substitute the value into the following formula.

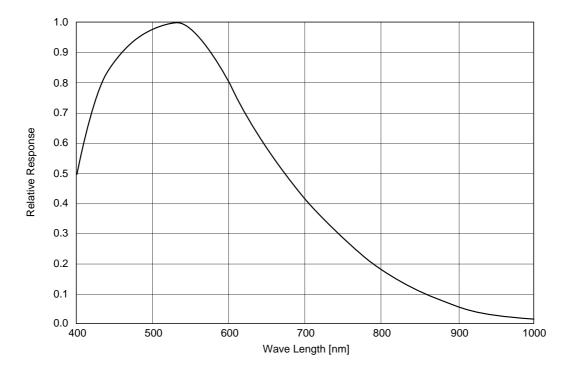
$$Lag = (Vlag/200) \times 100 [\%]$$



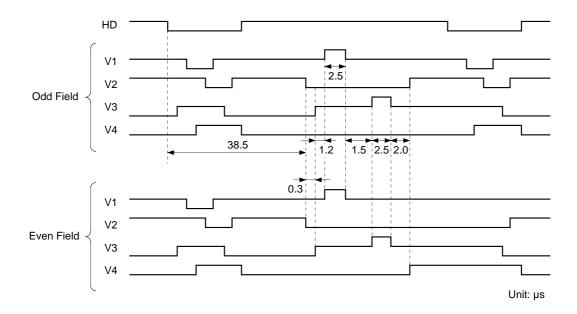


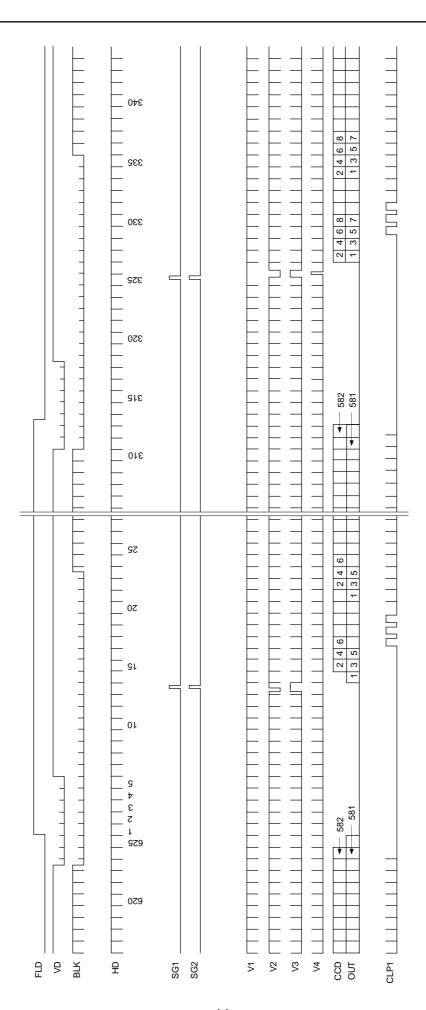
# **Spectral Sensitivity Characteristics**

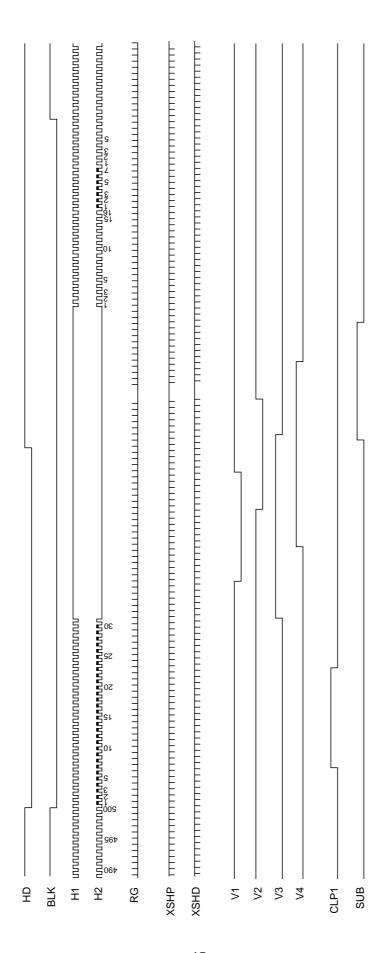
(Includes lens characteristics, excludes light source characteristics)



# **Sensor Readout Clock Timing Chart**







#### **Notes on Handling**

#### 1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material.
  Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

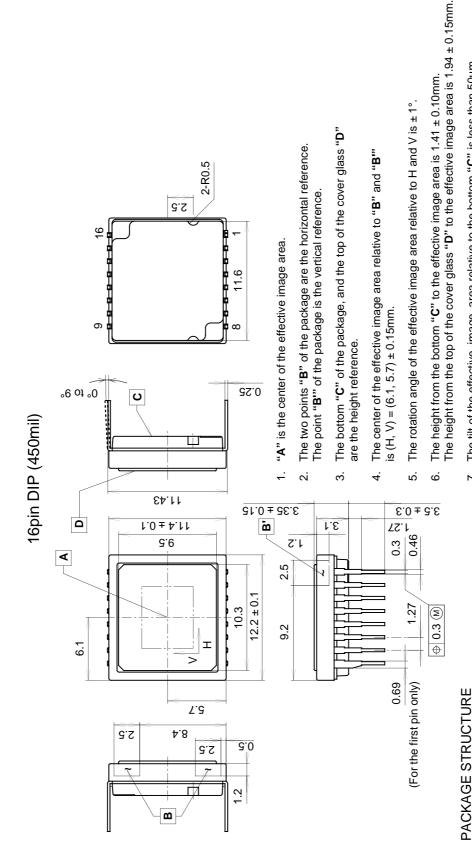
#### 2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.

#### 3) Dust and dirt protection

- a) Operate in clean environments (around class 1000 is appropriate).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.
- 4) Do not expose to strong light (sun rays) for long periods.
- 5) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- 6) CCD image sensors are precise optical equipment that should not be subject to mechanical shocks.

Unit: mm



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The tilt of the effective image area relative to the bottom "C" is less than 50µm. The tilt of the effective image area relative to the top "D" of the cover glass is less than 50µm.

The thickness of the cover glass is 0.75mm, and the refractive index is 1.5. ω.

GOLD PLATING

Plastic

PACKAGE MATERIAL

**LEAD TREATMENT** 

LEAD MATERIAL

**42 ALLOY** 

0.9g

PACKAGE WEIGHT

The notches on the bottom of the package are used only for directional index, they must not be used for reference of fixing. 6